Special Issue

AI Test

Message from the Guest Editors

Topics of interest include, but are not limited to:

- Quality models, quality attributes and metrics for AI applications, such as robustness, fairness, reliability and performance.
- Testing methods, techniques and tools for various aspects and activities of testing and quality assurance, especially for test case generation, test oracle, and test adequacy measurements.
- Test automation environment and platforms for AI applications and by employing AI techniques.
- Domain specific testing techniques and methods for various special domains of AI applications, such as AI applications in natural language processing such as ChatGPT, image recognitions, time series and Internet of Things data analysis, medical and healthcare, robotics, software code generation/debugging/design, etc.
- Testing and quality assurance for various specific AI techniques, such as clusters and classifiers, regression machine learning models, deep neural networks, big models, recurrent neural networks, etc.

Guest Editors

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Prof. Dr. Junhua Ding

Prof. Dr. Aktouf Oum-El-Kheir

Deadline for manuscript submissions

closed (31 January 2024)

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Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guestedited by leading experts in selected topics of interest.

Editor-in-Chief

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manuscripts are peer-reviewed and a first decision is provided to authors approximately 16.8 days after submission; acceptance to publication is undertaken in 2.4 days (median values for papers published in this journal in the first half of 2025).